

PowerMOS transistor

BUK437-400B

GENERAL DESCRIPTION

N-channel enhancement mode field-effect power transistor in a plastic envelope.
The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in general purpose switching applications.

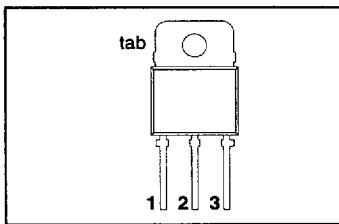
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	UNIT
V_{DS}	Drain-source voltage	400	V
I_D	Drain current (DC)	12	A
P_{tot}	Total power dissipation	180	W
$R_{DS(ON)}$	Drain-source on-state resistance	0.5	Ω

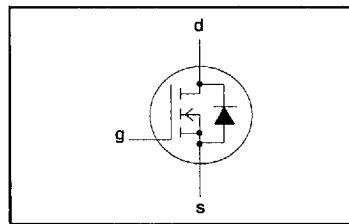
PINNING - SOT93

PIN	DESCRIPTION
1	gate
2	drain
3	source
tab	drain

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS}	Drain-source voltage	-	-	400	V
V_{DGR}	Drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	400	V
$\pm V_{GS}$	Gate-source voltage	-	-	30	V
I_D	Drain current (DC)	$T_{mb} = 25^\circ\text{C}$	-	12	A
I_D	Drain current (DC)	$T_{mb} = 100^\circ\text{C}$	-	7.6	A
I_{DM}	Drain current (pulse peak value)	$T_{mb} = 25^\circ\text{C}$	-	48	A
P_{tot}	Total power dissipation	$T_{mb} = 25^\circ\text{C}$	-	180	W
T_{stg}	Storage temperature	$T_{mb} = 25^\circ\text{C}$	-55	150	°C
T_j	Junction Temperature	-	-	150	°C

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th,j-mb}$	Thermal resistance junction to mounting base		-	-	0.69	K/W
$R_{th,j-a}$	Thermal resistance junction to ambient		-	45	-	K/W

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STATIC CHARACTERISTICS $T_{mb} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA}$	400	-	-	V
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	2.1	3.0	4.0	V
I_{DSS}	Zero gate voltage drain current	$V_{DS} = 400 \text{ V}; V_{GS} = 0 \text{ V}; T_J = 25^\circ\text{C}$	-	2	20	μA
I_{DS}	Zero gate voltage drain current	$V_{DS} = 400 \text{ V}; V_{GS} = 0 \text{ V}; T_J = 125^\circ\text{C}$	-	0.1	1.0	mA
I_{GSS}	Gate source leakage current	$V_{GS} = \pm 30 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nA
$R_{DS(ON)}$	Drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 6.5 \text{ A}$	-	0.45	0.5	Ω

DYNAMIC CHARACTERISTICS $T_{mb} = 25^\circ\text{C}$ unless otherwise specified

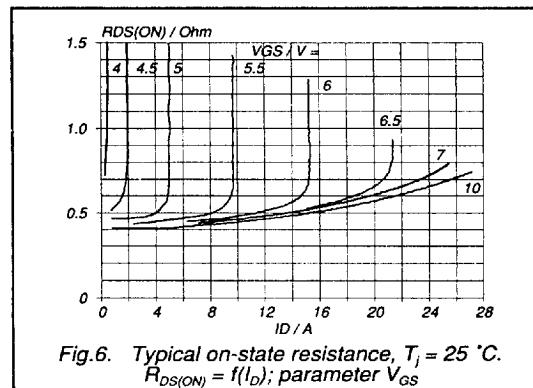
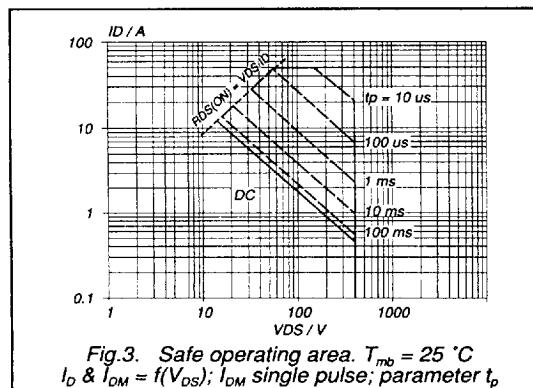
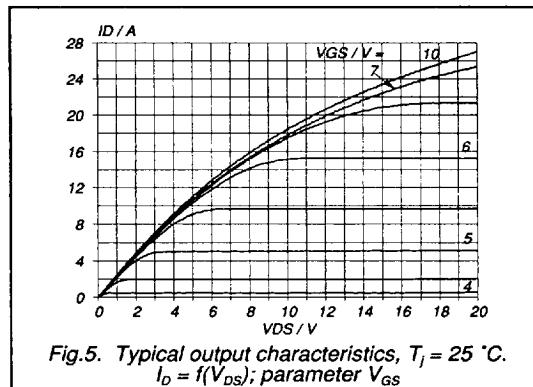
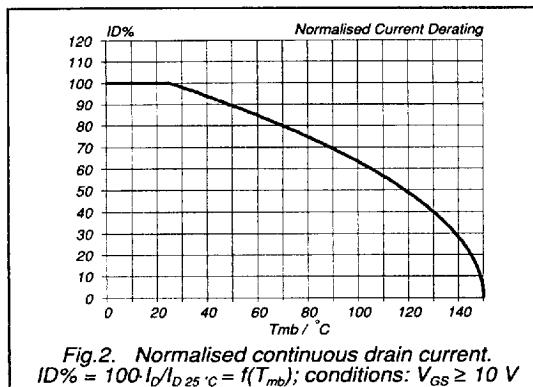
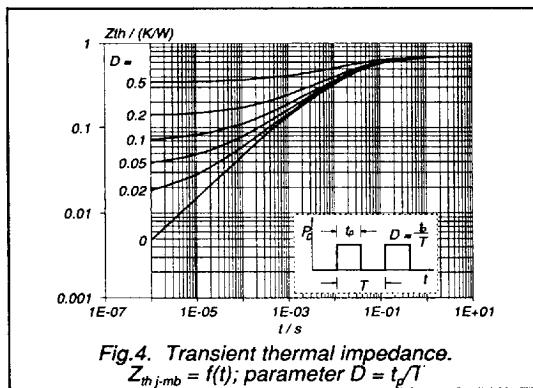
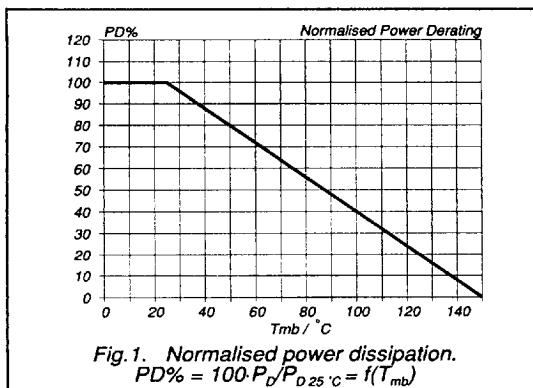
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g_{fs}	Forward transconductance	$V_{DS} = 25 \text{ V}; I_D = 6.5 \text{ A}$	5.0	8.0	-	S
C_{iss} C_{oss} C_{rss}	Input capacitance Output capacitance Feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	- - -	1500 170 70	1800 270 120	pF pF pF
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	Turn-on delay time Turn-on rise time Turn-off delay time Turn-off fall time	$V_{DD} = 30 \text{ V}; I_D = 2.8 \text{ A};$ $V_{GS} = 10 \text{ V}; R_{GS} = 50 \Omega;$ $R_{gen} = 50 \Omega$	- - - -	20 60 200 75	40 90 250 90	ns ns ns ns
L_d L_d' L_s	Internal drain inductance Internal drain inductance Internal source inductance	Measured from contact screw on tab to centre of die Measured from drain lead 6 mm from package to centre of die Measured from source lead 6 mm from package to source bond pad	- - -	5 5 12.5	- - -	nH nH nH

REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS $T_{mb} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{DR}	Continuous reverse drain current	-	-	-	14	A
I_{DRM} V_{SD}	Pulsed reverse drain current Diode forward voltage	$I_F = 14 \text{ A}; V_{GS} = 0 \text{ V}$	-	1.1	56 1.4	A V
t_r Q_{rr}	Reverse recovery time Reverse recovery charge	$I_F = 14 \text{ A}; -dI/dt = 100 \text{ A}/\mu\text{s};$ $V_{GS} = 0 \text{ V}; V_R = 100 \text{ V}$	-	500 6.0	-	ns μC

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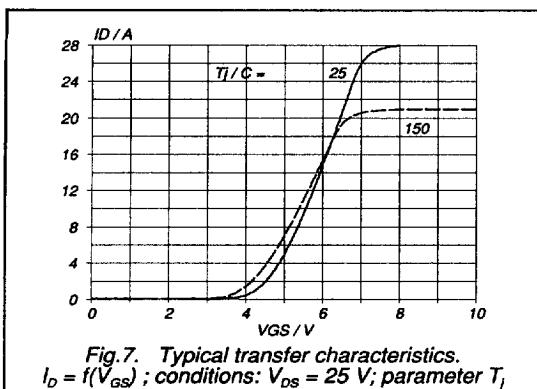


Fig.7. Typical transfer characteristics.
 $I_D = f(V_{GS})$; conditions: $V_{DS} = 25$ V; parameter T_j

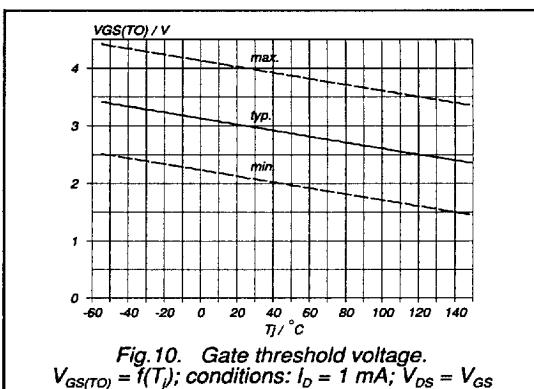


Fig.10. Gate threshold voltage.
 $V_{GS(TO)} = f(T_j)$; conditions: $I_D = 1$ mA; $V_{DS} = V_{GS}$

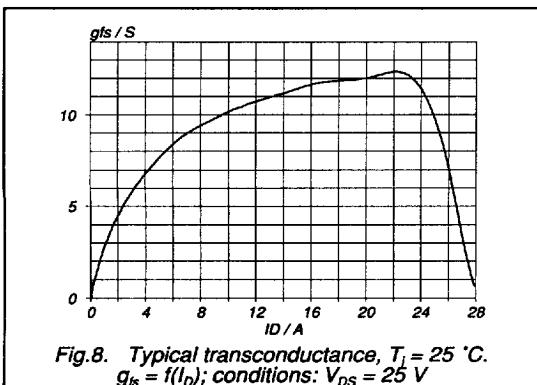


Fig.8. Typical transconductance, $T_j = 25$ °C.
 $g_{fs} = f(I_D)$; conditions: $V_{DS} = 25$ V

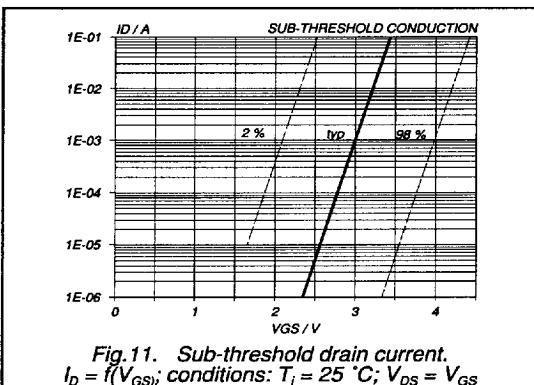


Fig.11. Sub-threshold drain current.
 $I_D = f(V_{GS})$; conditions: $T_j = 25$ °C; $V_{DS} = V_{GS}$

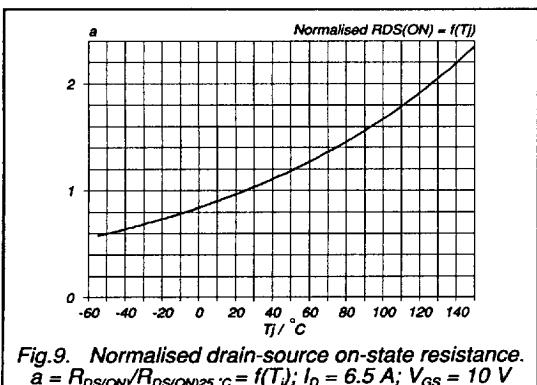


Fig.9. Normalised drain-source on-state resistance.
 $a = R_{DS(ON)}/R_{DS(ON)25\text{ }^{\circ}\text{C}} = f(T_j)$; $I_D = 6.5$ A; $V_{GS} = 10$ V

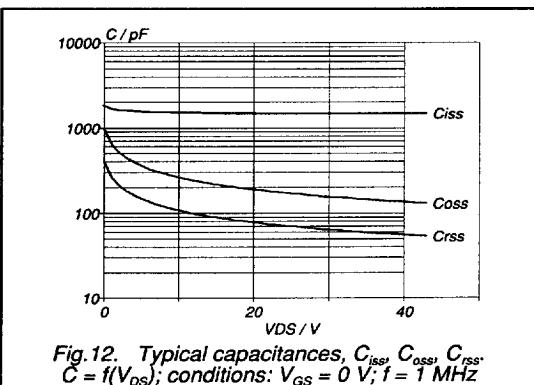


Fig.12. Typical capacitances, C_{iss} , C_{oss} , C_{rss} .
 $C = f(V_{DS})$; conditions: $V_{GS} = 0$ V; $f = 1$ MHz

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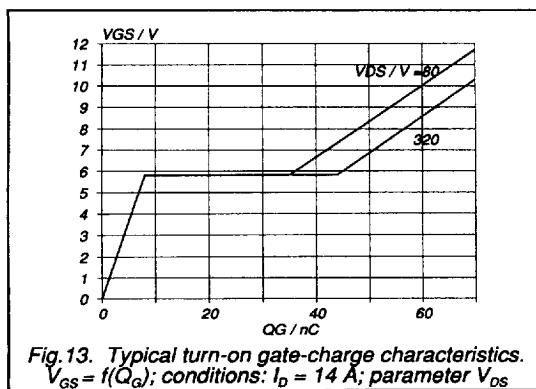


Fig.13. Typical turn-on gate-charge characteristics.
 $V_{GS} = f(Q_G)$; conditions: $I_D = 14 \text{ A}$; parameter V_{DS}

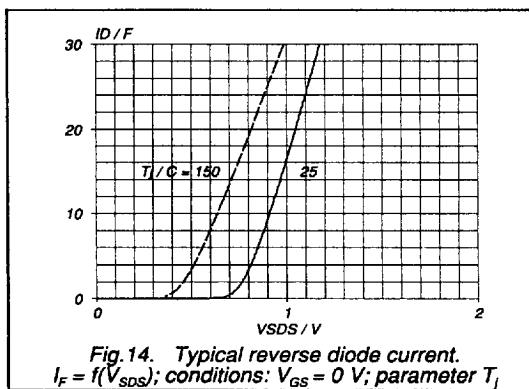


Fig.14. Typical reverse diode current.
 $I_F = f(V_{SDS})$; conditions: $V_{GS} = 0 \text{ V}$; parameter T_J